



POWER-MOS FET

FIELD EFFECT POWER TRANSISTOR

IRFF312,313

1.15 AMPERES
400, 350 VOLTS
 $R_{DS(ON)} = 5.0 \Omega$

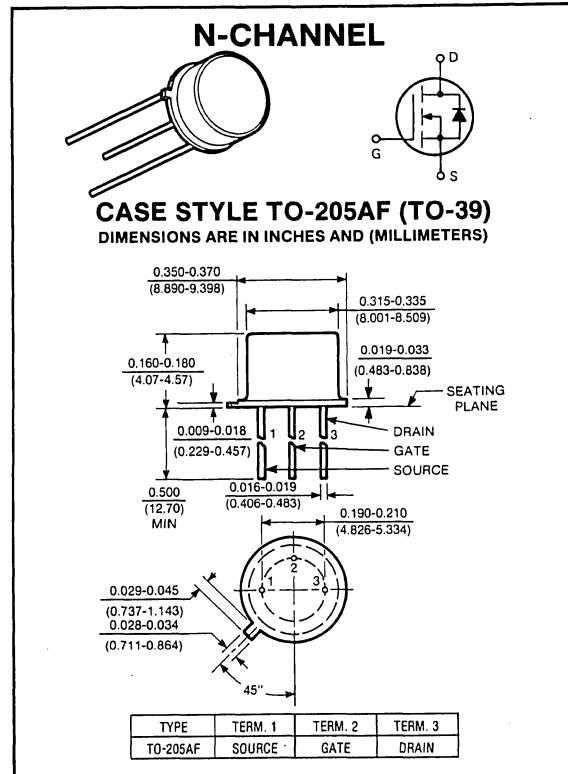
Preliminary

This series of N-Channel Enhancement-mode Power MOSFETs utilizes GE's advanced Power DMOS technology to achieve low on-resistance with excellent device ruggedness and reliability.

This design has been optimized to give superior performance in most switching applications including: switching power supplies, inverters, converters and solenoid/relay drivers. Also, the extended safe operating area with good linear transfer characteristics makes it well suited for many linear applications such as audio amplifiers and servo motors.

Features

- Polysilicon gate — Improved stability and reliability
- No secondary breakdown — Excellent ruggedness
- Ultra-fast switching — Independent of temperature
- Voltage controlled — High transconductance
- Low input capacitance — Reduced drive requirement
- Excellent thermal stability — Ease of paralleling



maximum ratings ($T_C = 25^\circ C$) (unless otherwise specified)

RATING	SYMBOL	IRFF312	IRFF313	UNITS
Drain-Source Voltage	V_{DSS}	400	350	Volts
Drain-Gate Voltage, $R_{GS} = 1M\Omega$	V_{DGR}	400	350	Volts
Continuous Drain Current @ $T_C = 25^\circ C$	I_D	1.15	1.15	A
Pulsed Drain Current ⁽¹⁾	I_{DM}	4.5	4.5	A
Gate-Source Voltage	V_{GS}	± 20	± 20	Volts
Total Power Dissipation @ $T_C = 25^\circ C$ Derate Above $25^\circ C$	P_D	15 0.12	15 0.12	Watts $W^\circ C$
Operating and Storage Junction Temperature Range	T_J, T_{STG}	-55 to 150	-55 to 150	$^\circ C$

thermal characteristics

Thermal Resistance, Junction to Case	$R_{\theta JC}$	8.33	8.33	$^\circ C/W$
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	175	175	$^\circ C/W$
Maximum Lead Temperature for Soldering Purposes: 1/16" from Case for 10 Seconds	T_L	260	260	$^\circ C$

(1) Repetitive Rating: Pulse width limited by max. junction temperature.

electrical characteristics ($T_C = 25^\circ C$) (unless otherwise specified)

CHARACTERISTIC	SYMBOL	MIN	TYP	MAX	UNIT
off characteristics					
Drain-Source Breakdown Voltage ($V_{GS} = 0V$, $I_D = 250 \mu A$)	IRFF312 IRFF313	BV _{DSS} 400 350	— —	— —	Volts
Zero Gate Voltage Drain Current ($V_{DS} = \text{Max Rating}$, $V_{GS} = 0V$, $T_C = 25^\circ C$) ($V_{DS} = \text{Max Rating} \times 0.8$, $V_{GS} = 0V$, $T_C = 125^\circ C$)	I _{DSS}	— —	— —	250 1000	μA
Gate-Source Leakage Current ($V_{GS} = \pm 20V$)	I _{GSS}	—	—	± 100	nA

on characteristics*

Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_D = 250 \mu A$)	$T_C = 25^\circ C$	$V_{GS(TH)}$	2.0	—	4.0	Volts
On-State Drain Current ($V_{GS} = 10V$, $V_{DS} = 10V$)		I _{D(ON)}	1.15	—	—	Amp
Static Drain-Source On-State Resistance ($V_{GS} = 10V$, $I_D = 0.8A$)		R _{DS(ON)}	—	—	5.0	Ohms
Forward Transconductance ($V_{DS} = 10V$, $I_D = 0.8A$)		g _{fs}	0.4	—	—	mhos

dynamic characteristics

Input Capacitance	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1 \text{ MHz}$	C _{iss}	—	385	600	pF
Output Capacitance		C _{oss}	—	70	200	pF
Reverse Transfer Capacitance		C _{rss}	—	12	40	pF

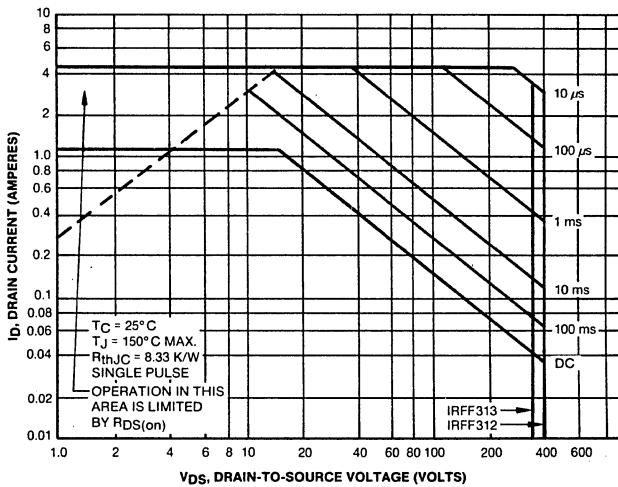
switching characteristics*

Turn-on Delay Time	$V_{DS} = 175V$ $I_D = 0.8A$, $V_{GS} = 15V$ $R_{GEN} = 50\Omega$, $R_{GS} = 12.5\Omega$ (R_{GS} (EQUIV.) = 10Ω)	t _{d(on)}	—	3	—	ns
Rise Time		t _r	—	10	—	ns
Turn-off Delay Time		t _{d(off)}	—	5	—	ns
Fall Time		t _f	—	8	—	ns

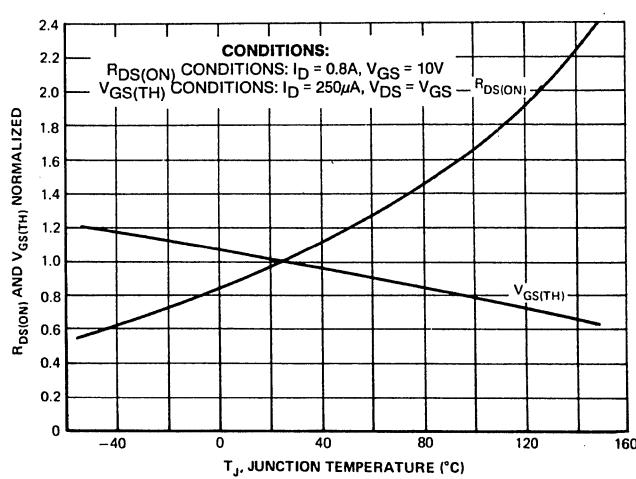
source-drain diode ratings and characteristics*

Continuous Source Current	I _S	—	—	1.15	A
Pulsed Source Current	I _{SM}	—	—	4.5	A
Diode Forward Voltage ($T_C = 25^\circ C$, $V_{GS} = 0V$, $I_S = 1.15A$)	V _{SD}	—	—	1.5	Volts
Reverse Recovery Time ($I_S = 1.35A$, $dI_S/dt = 100A/\mu s$, Max., $T_C = 125^\circ C$)	t _{rr}	—	380	—	ns

*Pulse Test: Pulse width $\leq 300 \mu s$, duty cycle $\leq 2\%$



MAXIMUM SAFE OPERATING AREA



TYPICAL NORMALIZED R_{DS(ON)} AND V_{GS(TH)} VS. TEMP.